

Substitute for Form 1449 A & B/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)				<i>Complete if Known</i>	
				Application Number	10/765,904
				Confirmation Number	2613
				Filing Date	January 29, 2004
				First Named Inventor	Markus MENGEL
				Art Unit	Not Yet Assigned
Examiner Name	Not Yet Assigned				
Attorney Docket Number	Q79656				
Sheet	1	of	1		

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
		Number	Kind Code ² (if known)		
SAT		US 6,473,176	B1	10/29/2002	Wang, et al.
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		US 5,886,810		03/23/1999	Siahpoushan, et al.
		US 5,744,721		04/28/1998	Varnum
		US 5,652,673		07/29/1997	Oakberg
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FOREIGN PATENT DOCUMENTS							
Examiner Initials*	Cite No. ¹	Foreign Patent Document			Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Translation ⁶
		Country Code ³	Number ⁴	Kind Code ⁵ (if known)			

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city, and/or country where published.	Translation ⁶
SAT		H. P. POVEL et al., "Two-dimensional polarimeter with a charge-coupled-device image sensor and a piezoelectric modulator," Applied Optics, July 1, 1994, pp. 4254-4259, Vol. 33, No. 19	
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		D. WRÓBLEWSKI et al., "Polarimetry of motional Stark effect and determination of current profiles DIII-D (invited)," Rev. Sci. Instrum., October 1992, Vol. 63, No. 10	
		M. TOTZECK et al., "Edge localization of subwavelength structures by use of polarization interferometry and extreme-value criteria," Applied Optics, December 1, 2000, Vol. 39, No. 34	
		M. TOTZECK et al., "High-resolution inspection of 2D-microstructures using multi-mode polarization microscopy," Proceedings of the 2 nd Conference on Design and Fabrication, 2000, Japan	
SAT		D. CLARKE and J. F. GRAINGER, "Polarized Light and Optical Measurement," Pergamon Press, Oxford, 1971	

Examiner Signature	/Samuel A. Turner/	Date Considered	05/05/2006
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IDS - 01/29/2004
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STATEMENT BY APPLICANT**

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		US 5 396 329		3/7/1995	BRITISH AEROSPACE PLC
		US 5 298 972		3/29/1994	HEWLETT-PACKARD COMPANY
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FOREIGN PATENT DOCUMENTS

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		Country Code ³	Number ⁴	Kind Code ⁵ (if known)			
SAT		DE	101 09 929	A1	11/22/2001	CARL ZEISS	
		EP	0 439 127	A2	7/31/1991	HEWLETT-PACKARD COMPANY	
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		JP	11-142291	A	5/28/1999	NIKON CORPORATION	Abstract
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SAT		WO	03/028073	A1	4/3/2003	NIKON CORPORATION	Claims

NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city, and/or country where published.	Translation ⁶
SAT		"OPTICAL SHOP TESTING", EDITED BY: DANIEL MALACARA, JOHN WILEY & SONS, INC., SECOND EDITION, PAGES 112-113, 1992, USA.	
SAT		MICHAEL I. SHRIBAK ET AL, "RETURN-PATH POLARIMETER FOR TWO DIMENSIONAL BIREFRINGENCE DISTRIBUTION MEASUREMENT", JULY 1999, SPIE, PAGES 144-145 AND 148-149, VOLUME 3654, DENVER COLORADO	
SAT		S. BEREZHNA, ET AL, "ACCURACY OF WHOLE-FIELD MAPPING BY JONES MATRIX FOURIER PHOTOPOLARIMETER", 2000, PROCEEDINGS OF SPIE, PAGES 81-89, VOLUME 4148	

Examiner Signature

/Samuel A. Turner/

Date Considered

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